Search Notes

Application/Control No.	l No. Applicant(s)/Patent under Reexamination	
10/669,805	CRAIGHEAD, MATTHEW J.	
Examiner	Art Unit	
Christopher B. Shin	2181	

SEARCHED					
Class	Subclass	Date	Examiner		
710	22-28,52- 56	6/13/2007	cs		
711	202-209	6/13/2007	cs		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
710	22,56	11/12/2007	cs	
711	208	11/12/2007	cs	
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
PLUS	6/13/2007	cs		
PALM for double patenting	6/13/2007	cs		
EAST (USPGPUB,USPAT,USOCR,FPRS,E PO,JPO,DERWENT,IBMTDB)	6/13/2007	cs		
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